Charge Recycling Sense Amplifier Based Logic: Securing Low Power Security IC's against Differential Power Analysis

Kris Tiri and Ingrid Verbauwhede

Contact Address:

UCLA Electrical Engineering Department,

7440B Boelter Hall, P.O. Box 951594, Los Angeles, CA 90095-1594

{tiri, ingrid}@ee.ucla.edu

Abstract

Charge Recycling Sense Amplifier Based Logic is presented. This logic is derived from Sense Amplifier Based Logic, which is a logic style with signal independent power consumption that is capable to protect security devices such as Smart Cards against power attacks. Experimental results show that utilization of advanced circuit techniques save 20% in power consumption and 63% in peak supply current and that the logic style preserves the energy masking behavior.

I INTRODUCTION

Encryption algorithms have been designed to be secure against cryptanalysis that has access to plaintext and ciphertext. The physical implementation however, provides the attacker with important information. Numerous attacks have been presented that use 'side channels', such as time delay and power consumption, as an extra source of information to find the secret key [1]. Especially the Differential Power Analysis (DPA) [2] is of great concern. It is very effective in finding the secret key and can be mounted quickly with off-the-shelf devices. The attack is based on the fact that logic operations have power characteristics that depend on the input data. It relies on statistical analysis to extract the information from the power consumption that is correlated to the secret key.

Scores of countermeasures have been presented that try to conceal the supply current variations at the architectural or the algorithmic level. Yet, they are not really effective or practical against DPA and/or its derivatives, as the variations actually originate at the logic level. On the other hand, implementing the encryption module in a logic style, for which a logic gate has at all times a constant power consumption independently of signal transitions, removes the foundation of DPA and is an effective means to halt DPA [3]. One such logic style available is Sense Amplifier Based Logic (SABL) [4].

Many present-day embedded applications have cryptographic capabilities for authentication and confidentiality. For these battery-powered devices much focus is on lower power design. We have analyzed advanced circuit techniques to reduce the power consumption of SABL.

Charge Recycling SABL (CRSABL) recycles the charge stored at one output node in the evaluation phase to partially charge the output and the internal nodes to an intermediate voltage in the precharge phase. This technique achieves a reduction in power consumption of 20%.

Since CRSABL reuses internally stored charge, it also benefits from a reduction in *di/dt* and peak supply current. As a result, the supply bounce, often a critical problem for signal integrity, is lowered. Furthermore, CRSABL reduces the number of clocked transistors with one third.

Section II describes CRSABL. The discussion consists of (1) a description of the CRSABL inverter, (2) design rules for cascading charge recycling dynamic gates, (3) the energy-delay performance and (4) techniques to overcome destructive charge sharing effects in arbitrary CRSABL gates. In section III, an experiment is setup to compare the performance and energy masking behavior of CRSABL and SABL. Finally a conclusion will be given.

II CHARGE RECYCLING SABL

A. Inverter

The CRSABL inverter is depicted in Figure 1 (right). The gate differs in one point from the sense amplifier of the StrongArm110 flip-flop [6], which is the gate SABL is derived from [4]. The SABL inverter, which equals the sense amplifier, is depicted in Figure 1 (left). The two clocked pmos transistors that precharge the output nodes of the sense amplifier to the supply voltage VDD, are removed. Instead, they are replaced by one clocked pmos transistor between the output nodes.

Figure 2 shows a switching event of the CRSABL inverter. At the onset of the precharge phase (clk-signal low), node Z is disconnected from GND and the output nodes are shorted. The high output drops and the low output rises in order to converge to the same voltage, which is VDD – V_t. V_t is the threshold voltage. At that instant, the pmos transistors of the cross-coupled inverter are turned off. Meanwhile, the internal nodes X and Y have been precharged to VDD – $2V_t$. During the subsequent evaluation phase (clk-signal high), the gate will evaluate to a differential output as soon as one transistor of the differential input pair provides a path to GND.

Figure 2 also shows a switching event of the SABL inverter for the same inputs. CRSABL has both a lower total power consumption and a smaller peak current. The transistor sizes of both gates are optimized for minimum power consumption.

CRSABL consumes less power for two reasons. The first effect is charge recycling. The charge stored on the high output node during the evaluation phase is used to partially charge the low output node during the precharge phase. As a result, less charge has to come from the power supply. Secondly, the output and the internal nodes are only precharged to VDD – V_t and VDD – $2V_t$ respectively. This is one threshold voltage below the

precharge voltages of SABL. Since one output and all internal nodes, are discharged in every cycle, the lower the precharge voltages are, the lower the power consumption will be.

The peak supply current is smaller since less charge is required but also because the precharge current is not anymore supplied by clocked transistors, which are entirely open and provide a high peak current.

B. Cascading Gates

CRSABL, like SABL, is a dynamic logic style. Dynamic logic is connected using either domino logic, in which each gate is extended with a pair of inverters, or np-logic, in which n- and p-type gates are alternated.

CRSABL can not be connected according to the np-logic rules. The output signals of the p-type gate are pre-'dis'-charged to V_t. In this regime, the input transistors of the subsequent n-type gate have a very high leakage current. The charge on the output nodes would quickly leak away and the cross-coupled inverter would switch. Furthermore, any noise insertion turns the transistors on and accelerates the process.

CRSABL can only be cascaded using domino logic. Yet, static inverters should not be used. They suffer from a direct path current when their input is at V_t. There are inverters that recover a full swing at the output without direct path current. Figure 3 (left) uses a high V_t pmos transistor. While this requires extra masks and processing steps, more and more designs nowadays use high V_t transistors to control subthreshold currents. Figure 3 (middle) [5] uses an enable signal to stop the direct path current. This requires 1 additional transistor and the generation of the enable signal. Finally, the circuit in Figure 3 (right) [5] consists of only 2 regular transistors driven by both output signals. This circuit has poor drive strength, as the current does not directly come from the supply.

C. Performance

This section compares the energy-delay characteristics of CRSABL and SABL. Two circuits are implemented: a CRSABL inverter extended with a pair of inverters of Figure 3 (right); and a SABL inverter extended with a pair of static inverters. The circuits are implemented in a 0.18μm, 1.8V CMOS technology. Simulations are done in HSPICE.

Measurements are done with the setup depicted in Figure 4 [7]. Four measurements are reported. E_{int} includes the power dissipated on switching the internal nodes, but excludes the power dissipated on the load capacitance. E_{data} and E_{clk} present the portion of the gray and black inverters' power consumption dissipated on the gate. Finally, the delay is measured between the 50% transition points of the input and output in the evaluation phase. The delay in the precharge phase is insignificant. All gates precharge in parallel. Note that the power measurements reflect precharge and evaluation phase.

Figure 5 shows the minimum energy-delay curves for C_l equal to 10fF in function of the transistor sizes. SABL achieves a lower minimum Energy Delay Product (EDP) then CRSABL. The minima are 7.2e-24 and 10.4e-24 respectively. For Smart Card applications however, speed performance is not important. Most Smart Cards have an internal clock frequency ranging from 10 to 20 MHz. Current state-of-the-art has a maximum internal clock frequency of a mere 55MHz [9]. For Smart Cards and battery-operated devices, the energy consumption per cycle, aka the Power Delay Product (PDP), is a better measure. CRSABL achieves 25.7fJ compared to 34.3fF for SABL.

Table I summarizes the energy-delay characteristics for the circuits with minimum PDP. A reduction of the clock load from 3 to 2 transistors has saved 41% in E_{clk}. E_{int} and E_{tot} have been reduced with 24% and 25% respectively. The tradeoff is with an increase in delay of 68%.

D. Charge Sharing Effects

CRSABL gates are built by replacing the input differential pair with a differential pull down network (DPDN). A special DPDN that for a differential input connects all internal nodes to an output node should be used to achieve constant power consumption [4]. Figure 6 (left) shows the CRSABL AND-gate extended with designated inverters.

This circuit however, suffers from charge sharing, which is a result from incompletely loaded internal nodes. Figure 7 (top) and (middle) show how this can lead to failure. Worst-case charge sharing occurs when the input signals have been precharged before the falling edge of the clock. When A becomes 1, charge from node nand1 will be used to charge node X. As a result, the cross-coupled inverter, which was in a metastable

state, will choose side. If subsequently $\overline{B}$ becomes 1 the cross-coupled inverter keeps state and the gate produces an incorrect output.

SABL experiences destructive charge sharing as well. Here, the remedy consists of increasing the length and thus the resistance of transistor M_1. This decreases the gain in the feedback loop such that node and1 can discharge; compensate for the drop in nand1; and switch the cross-coupled inverter back to the other side. This is not a viable solution for CRSABL as the length of M_1 would become too large. Because of the lower precharge voltage, the voltage difference between nodes and1 and nand1 after charge sharing is too significant.

The resistance of M_1 can also be increased by applying a low bias voltage V such that transistor M_1 is only turned on to close the feedback loop of the cross-coupled inverters whenever its drain or source is almost at 0. The shortcoming of this approach is that a bias voltage needs to be distributed to all gates. A better solution is to use the feedback network depicted in Figure 6 (right). This circuit will turn on transistor M_1 when 1 output node has become 1. Figure 7 (bottom) shows the output voltages of the CRSABL AND-gate with feedback network. Simulations indicate that the feedback network does not result in a delay penalty.

III Experimental Results

We have built a set of basic gates and implemented a typical cryptographic function in order to evaluate CRSABL with respect to the energy-delay performance and energy masking behavior of SABL. All gates are extended with inverters and have been optimized for minimum PDP. The CRSABL gates use the feedback network and the SABL gates an appropriate sizing of transistor M_1 to avoid destructive charge sharing effects. Measurements have been performed according the technique described in section IIC.

The basic gates are the AND- and XOR-gate. This is a sufficient set to implement any logic function. The differential inverter is redundant as differential logic has both the true and the false output. The OR-gate is derived from the AND-gate by exchanging the inputs. Table II, which has been derived for a C_l of 10fF, shows that there is reduction of roughly 25% in E_{tot}. The delay increase is around 43%.

With this set of cells we have implemented the S9 substitution box of the Kasumi algorithm, the encryption algorithm in the 3G cellular standard [8]. After synthesis with DesignAnalyzer, the module has a maximum logic depth of 5 and consists of 86 XOR- and 46 AND-gates.

Table III summarizes the simulation results. The reduction of 20% in E_{tot} comes from a combined reduction of 18% in E_{int} and 43% in E_{clk}. There is an increase of 34% in the delay of the module. Note that the delay of the module is significantly smaller than 5 times the delays presented in Table II. Consequently, the standard load for CRSABL and SABL is much smaller than 10fF.

CRSABL preserves the energy masking behavior of SABL. Both NED and NSD, which are the normalized absolute variation and the normalized standard deviation of the energy per cycle, are small.

Figure 8 shows the statistical properties of the instantaneous supply current. The mean current is a representative switching event. The point wise absolute variation and standard deviation are small throughout the entire event. Note that both logic styles have a comparable absolute variation and standard deviation. The increase in relative energy variation in Table III is mainly the effect of a reduction of the normalization factor, which is the mean energy consumption. Note also that the peak supply current drops from 8.9mA to 3.3mA, a reduction of 63%.

IV CONCLUSIONS

We have presented a logic style to secure low power security IC's against differential power analysis. Experimental results have shown that through charge recycling and lower precharge voltages, Charge Recycling SABL achieves a 20% reduction in the total power consumption and a 63% reduction in the peak supply current of SABL. CRSABL preserves the resistance of SABL against power attacks. It operates with the same minor variation on the energy characteristics.

V REFERENCES

1. E. Hess, N. Janssen, B. Meyer and T. Schuetze, “Information Leakage Attacks Against Smart Card Implementations of Cryptographic Algorithms and Countermeasures – a Survey,” Proc. Of EUROSMART, pp. 55–64, 2000.
2. P. Kocher, J. Jaffe and B. Jun, “Differential Power Analysis,” Proc. of Advances in Cryptology, pp. 388-397, 1999.
3. K. Tiri and I. Verbauwhede, “Securing Encryption Algorithms against DPA at the Logic Level: Next Generation Smart Card Technology,” Proc. Workshop on Cryptographic Hardware and Embedded Systems, Lecture Notes in Computer Science Volume 2779, pp. 125–136, Sept. 2003.
4. K. Tiri, M. Akmal and I. Verbauwhede, “A Dynamic and Differential CMOS Logic with Signal Independent Power Consumption to Withstand Differential Power Analysis on Smart Cards,” Proc. 28th IEEE European Solid-State Circuits Conference, pp. 403-406, Sept. 2002.
5. B. Kong, J. Choi, S. Lee and K. Lee, “Charge Recycling Differential Logic (CRDL) for Low Power Application,” IEEE J. Solid-State Circuits, vol. 31, pp. 1267–1276, Sept. 1996.
6. J. Montanaro et al., “A 160-MHz, 32-b, 0.5-W CMOS RISC microprocessor,” IEEE J. Solid-State Circuits, vol. 31, pp. 1703–1714, Nov. 1996.
7. V. Stojanovic and V. G. Oklobdzija, “Comparative analysis of masterslave latches and flip-flops for high-performance and low-power systems,” IEEE J. Solid-State Circuits, vol. 34, pp. 536–548, Apr. 1999.
8. Specification of the 3GPP confidentiality and integrity algorithms (3GPP TS 35.202 version 5.0.0 Release 5), http://pda.etsi.org/pda, June 2002.
9. SLE88CX720P Short Product Information, http://www.infineon.com, June 2003.

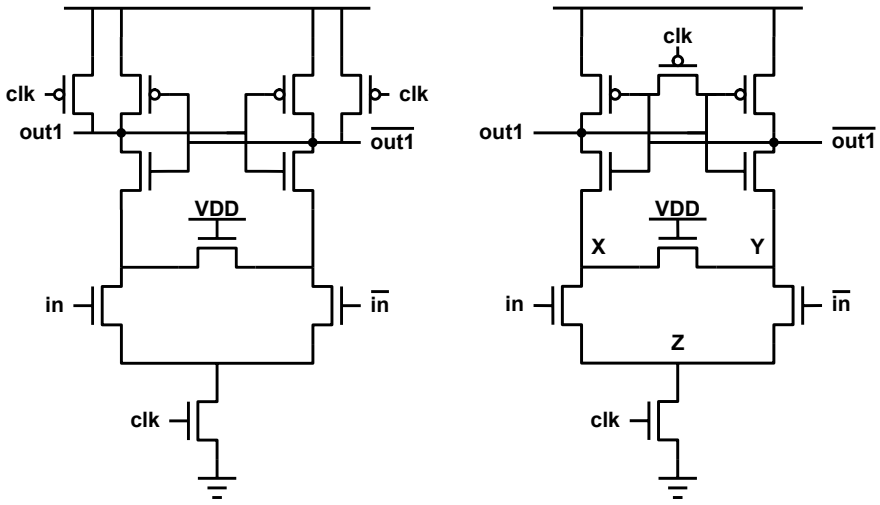

Figure 1. Inverter: SABL (left); and CRSABL (right)

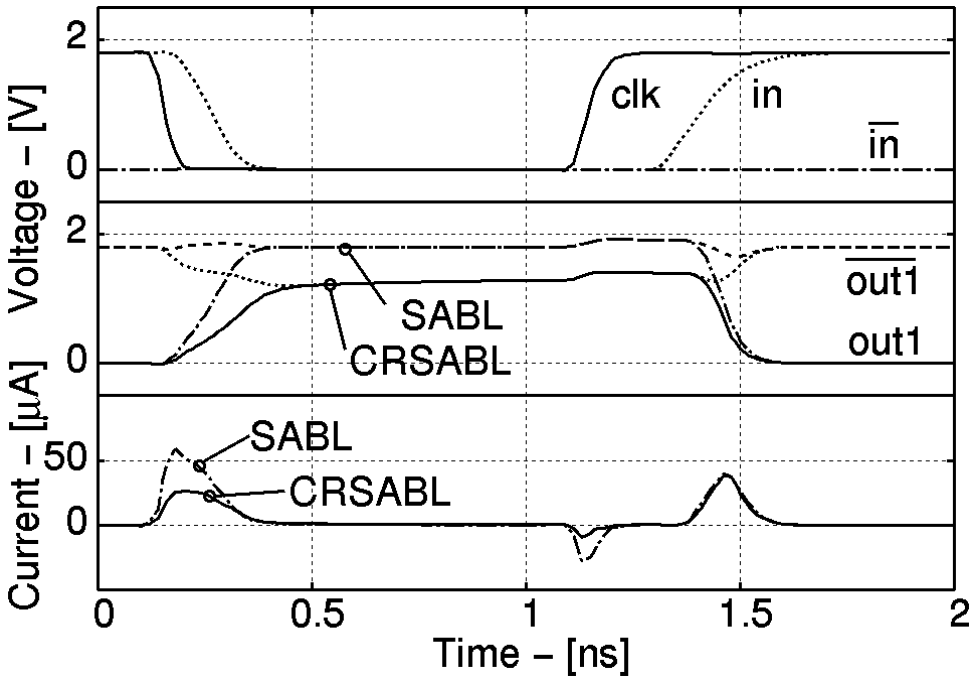

Figure 2. Simulated waveform transients of inverter: input (top); output (middle); and current (bottom)

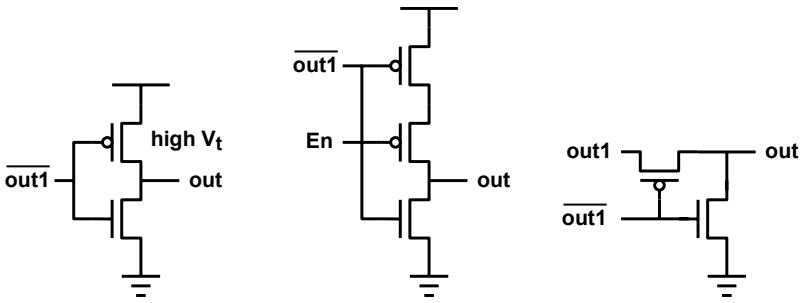

Figure 3. Inverters without direct path current

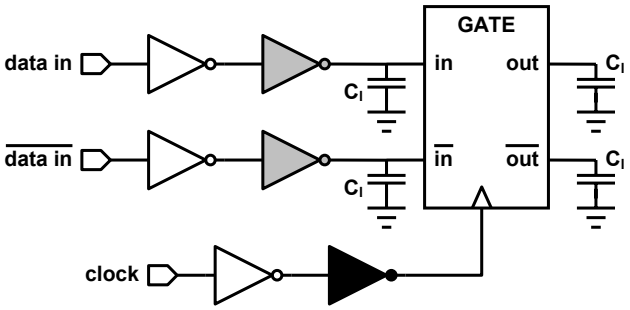

Figure 4. Measurement setup

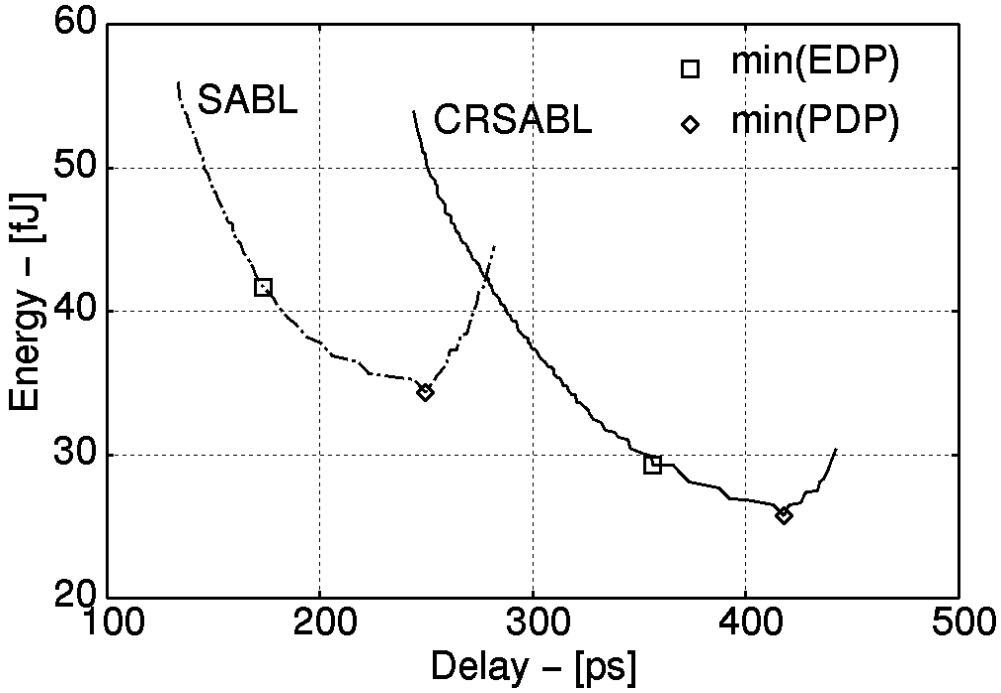

Figure 5. Energy-delay tradeoff of inverter

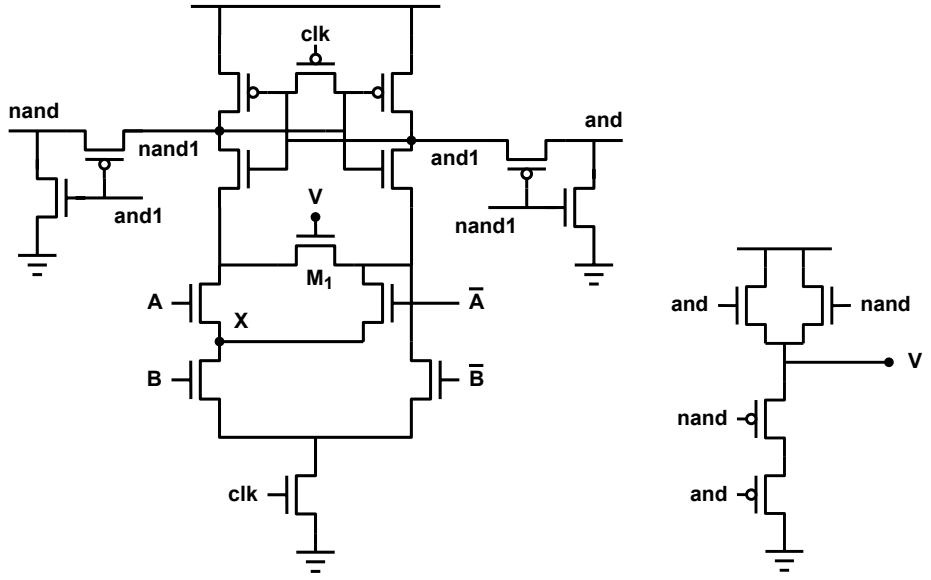

Figure 6. AND gate (left); and feedback network (right)

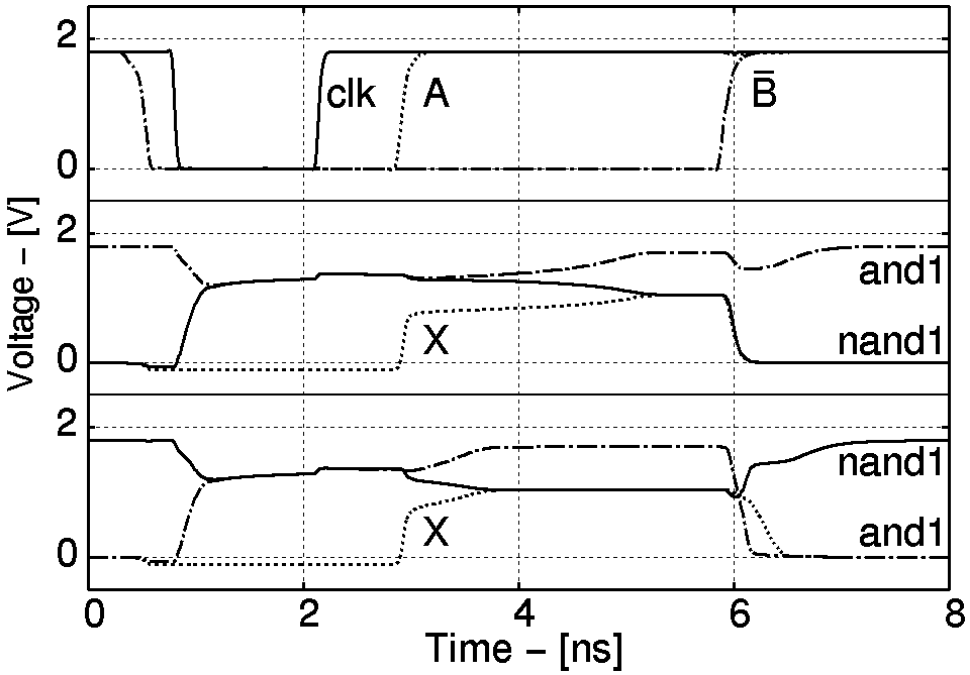

Figure 7. Simulated waveform transients: input (top); output (middle); and output with feedback (bottom)

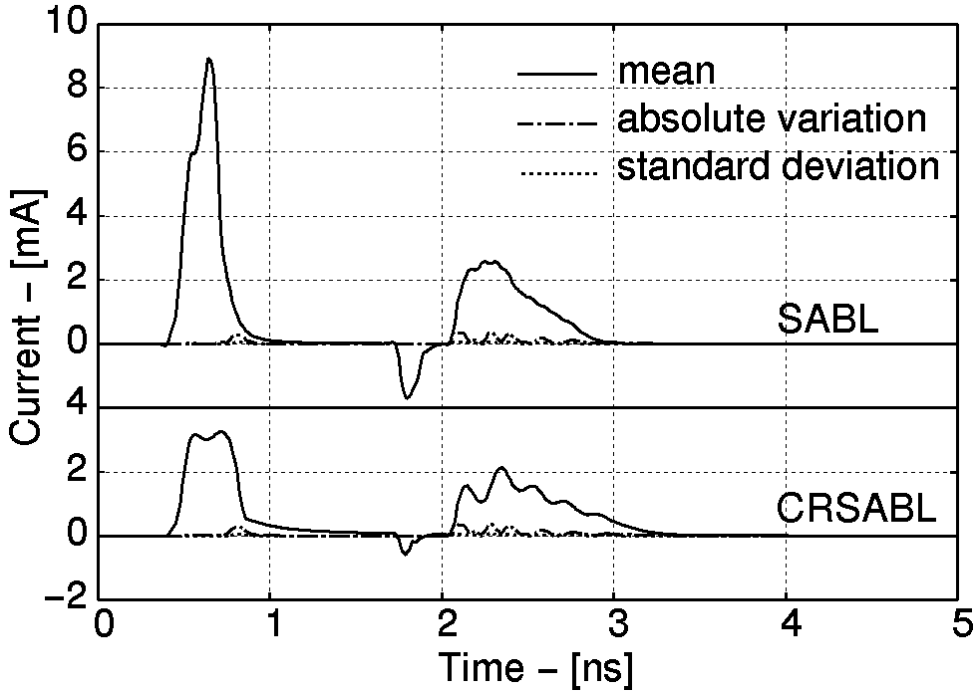

Figure 8. Typical supply current of S9box

Table I Energy-delay characteristics of inverter

	E_{int} (fJ)	E_{data} (fJ)	E_{clk} (fJ)	E_{tot} (fJ)	delay (ps)
SABL	**28.7**	**0.7**	**5.0**	**34.3**	**249**
CRSABL	**21.9**	**0.9**	**2.9**	**25.7**	**418**

Table II Energy-delay characteristics basic cells

	AND		XOR	
	E_{tot} (fJ)	Delay (ps)	E_{tot} (fJ)	Delay (ps)
SABL	42.7	312	48.7	325
CRSABL	33.1	452	35.5	459

Table III Energy-delay characteristics of S9box

	NED (e-3)	NSD (e-7)	E_{tot} (pJ)	delay (ps)
SABL	5	5	5.94	696
CRSABL	13	11	4.75	932